TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74AC377P,TC74AC377F

#### Octal D-Type Flip-Flop

The TC74AC377 is an advanced high speed CMOS OCTAL D-TYPE FLIP FLOP fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This 8-bit D-type flip-flop is controlled by a clock input (CK) and an enable input (  $\overline{G}$  )

The signal level applied to the D inputs are transferred to Q outputs during the positive going transition of CK.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### Features

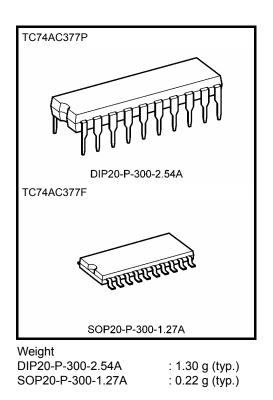
- High speed:  $f_{max} = 140 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 8 \ \mu A \ (max)$  at  $Ta = 25^{\circ}C$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24 \text{ mA} (\text{min})$

Capability of driving  $50 \Omega$  transmission lines.

- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range:  $V_{CC}$  (opr) = 2 to 5.5 V
- Pin and function compatible with 74F377

#### **Pin Assignment**

	· · ·	$\neg$		
G	1 🔲	$\mathbf{\nabla}$	20	V <sub>cc</sub>
Q1	2 C 3 C 4 C 5 C		20 19 18 17 16 15 14 13 12 11	Q8
D1	з 🗖		18	D8
D2	4 <b>C</b>		17	D7
Q2 Q3	5 🗖		<b>þ</b> 16	Q7
Q3	6 🗖		15	Q6
D3	7 <b>C</b>		14	D6
D4	8 🗖		13	D5
Q4	6 C 7 C 8 C 9 C		12	Q5
GND	10 <b>[</b>		11	СК
	(TOI	P VIE	W)	



## **TOSHIBA**

### IEC Logic Symbol

<u>б</u> <u>(1)</u> ск <u>(11)</u>	G1 > 1C2	
$\begin{array}{c} D1 & \underline{(3)} \\ D2 & \underline{(4)} \\ D3 & \underline{(7)} \\ D4 & \underline{(8)} \\ D5 & \underline{(13)} \\ D6 & \underline{(14)} \\ D7 & \underline{(17)} \\ D7 & \underline{(18)} \end{array}$	2 D	(2) Q1 (5) Q2 (6) Q3 (9) Q4 (12) Q5 (15) Q6 (16) Q7 (19) Q8
D8 (10)		- Q8

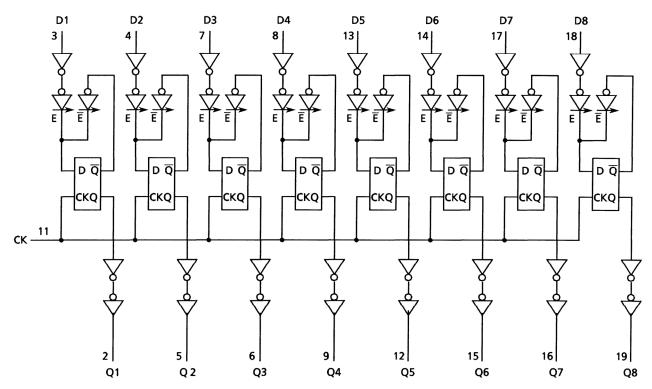
#### Truth Table

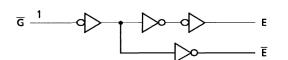
	Inputs	Output	
Ğ	СК	D	Q
Н	Х	Х	No Change
L		L	L
L		Н	Н
Х	$\neg$	Х	No Change

X: Don't care

### **TOSHIBA**

#### System Diagram





#### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5 to 7.0	V
DC input voltage	V <sub>IN</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	Vout	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	IIK	±20	mA
Output diode current	Іок	±50	mA
DC output current	lout	±50	mA
DC V <sub>CC</sub> /ground current	Icc	±200	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T <sub>stg</sub>	-65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65°C. From Ta = 65 to 85°C a derating factor of -10 mW/°C should be applied up to 300 mW.

#### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0 to 5.5	V	
Input voltage	VIN	0 to V <sub>CC</sub>	V	
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	-40 to 85	°C	
Input rise and fall time	dt/dV	0 to 100 (V_{CC} = 3.3 $\pm$ 0.3 V)	ns/V	
	uvuv	0 to 20 (V_{CC} = 5 $\pm$ 0.5 V)	ns/v	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

#### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics Symbol		Test Condition				-	Га = 25°С	)	Ta = -40 to 85°C		Unit
				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	onic	
					2.0	1.50		_	1.50	_	
High-level input voltage	VIH		—		3.0	2.10	—	—	2.10	—	V
					5.5	3.85	—	_	3.85	_	
					2.0	—	—	0.50	—	0.50	
Low-level input voltage	VIL		—		3.0	—	—	0.90	—	0.90	V
Ŭ					5.5		_	1.65	_	1.65	
	V <sub>OH</sub>				2.0	1.9	2.0	—	1.9	—	
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA		3.0	2.9	3.0	—	2.9	—	
High-level output					4.5	4.4	4.5	_	4.4		v
voltage			I <sub>OH</sub> = -4 mA		3.0	2.58	—	—	2.48	—	
			I <sub>OH</sub> = -24 mA		4.5	3.94	—	—	3.80	—	
			I <sub>OH</sub> = -75 mA	(Note)	5.5		_	_	3.85		
	V <sub>OL</sub>				2.0	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 50 μA		3.0	—	0.0	0.1	—	0.1	
Low-level output		V <sub>IN</sub> = V <sub>IH</sub> or			4.5	_	0.0	0.1	_	0.1	v
voltage	VOL		$I_{OL} = 12 \text{ mA}$		3.0	—	—	0.36	—	0.44	v
			$I_{OL} = 24 \text{ mA}$		4.5	—	—	0.36	—	0.44	
			$I_{OL} = 75 \text{ mA}$	(Note)	5.5	—	—	—	—	1.65	
Input leakage current	I <sub>IN</sub>	$V_{IN} = V_{CC}$ or GND		5.5		—	±0.1		±1.0	μA	
Quiescent supply current	ICC	V <sub>IN</sub> = V <sub>C</sub>	<sub>C</sub> or GND		5.5	_	_	8.0	_	80.0	μA

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

#### Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Test Condition			Unit
			V <sub>CC</sub> (V)	Limit	Limit	
Minimum pulse width	t <sub>W (L)</sub>		$\textbf{3.3}\pm\textbf{0.3}$	8.0	8.0	20
(CK)	t <sub>W (H)</sub>	—	$5.0\pm0.5$	5.0	5.0	ns
Minimum set-up time			$3.3\pm 0.3$	8.0	8.0	
(D-CK)	t <sub>s</sub>	ls —	$5.0\pm0.5$	4.0	4.0	ns
Minimum set-up time			$\textbf{3.3}\pm\textbf{0.3}$	9.0	9.0	20
( G -CK)	t <sub>s</sub>	—	$5.0\pm0.5$	4.0	4.0	ns
Minimum hold time	t <sub>h</sub>		$\textbf{3.3}\pm\textbf{0.3}$	1.0	1.0	20
			$5.0\pm0.5$	1.0	1.0	ns

#### AC Characteristics (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 $\Omega$ , input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40 to 85°C		Unit
	- ,		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
Propagation delay time	t <sub>pLH</sub>		$3.3\pm 0.3$	_	10.6	17.6	1.0	20.0	ns
(CK-Q)	t <sub>pHL</sub>		$5.0\pm0.5$	—	7.4	10.6	1.0	12.0	
Maximum clock	f		$\textbf{3.3}\pm\textbf{0.3}$	50	95		50	_	MHz
frequency	f <sub>max</sub>		$5.0\pm0.5$	80	140	_	80	_	
Input capacitance	C <sub>IN</sub>	—		—	5	10	_	10	pF
Power dissipation	C <sub>PD</sub>				30				pF
capacitance	(Note)	—			50				Ы

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$  (per F/F)

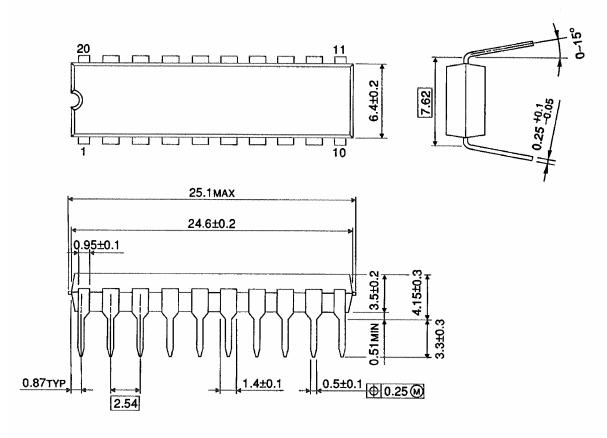
And the total CPD when n pcs. of flip flop operate can be gained by the following equation:

 $C_{PD (total)} = 20 + 10 \cdot n$ 

#### **Package Dimensions**

DIP20-P-300-2.54A

Unit : mm



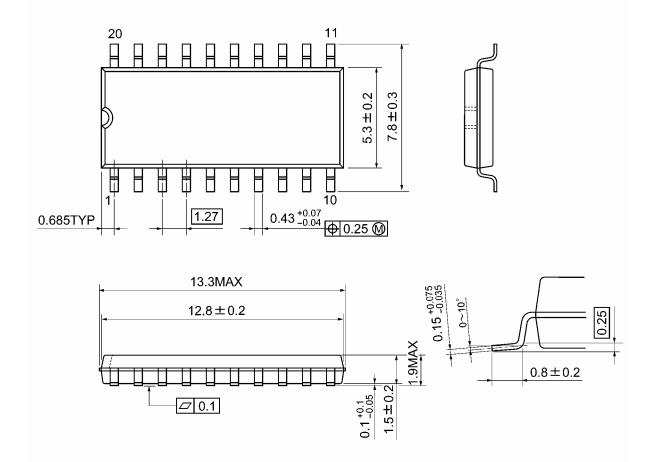
Weight: 1.30 g (typ.)

### **TOSHIBA**

#### Package Dimensions

SOP20-P-300-1.27A

Unit: mm



Weight: 0.22 g (typ.)

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20070701-EN GENERAL

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